Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	113	356/636.ccls. and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2006/02/05 19:29
L2	0	1 and heat\$3 and (edge adj roughness) and (critical adj dimension\$1)	US-PGPUB; USPAT	OR	ON	2006/02/05 19:27
L3	0	1 and heat\$3 and (edge adj roughness)	US-PGPUB; USPAT	OR	ON	2006/02/05 19:27
L4	0	1 and (edge adj roughness)	US-PGPUB; USPAT	OR	ON	2006/02/05 19:27
L5	0	reflow and heat\$3 and (edge adj roughness) and (critical adj dimension\$1)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 19:27
L6	1	heat\$3 and (edge adj roughness) and (critical adj dimension\$1)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 19:28
L7	71	heat\$3 and (edge adj roughness)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 19:29
L9	21	7 and @pd<="20030822"	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 19:32
L10	O	((non-lithographic adh shrink) and photoresist and melting and (edge adj roughness) and (critical adj dimension)).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/05 19:34
S1	581	smooth\$5 with rough\$4 with heat	US-PGPUB; USPAT	OR	ON	2005/10/15 19:11
S2	3	S1 same monitor\$3	US-PGPUB; USPAT	OR	ON	2005/10/04 12:39
S3	158	S1 and semiconductor	US-PGPUB; USPAT	OR	ON	2005/10/04 12:40
S4	108	S3 and melt\$3	US-PGPUB; USPAT	OR	ON	2005/10/04 12:41
S5	2	(smooth\$5 with roughness) and (heat adj polish\$3)	US-PGPUB; USPAT	OR	ON	2005/10/04 13:49
S6	9	(smooth\$5 with roughness) and (melt\$3 with photoresist)	US-PGPUB; USPAT	OR	ON	2005/10/04 14:53
S7	11	(smooth\$5 with roughness) and ((heat\$3 or melt\$3) with photoresist) and (glass adj transition\$3)	US-PGPUB; USPAT	OR	ON	2005/10/04 14:55
S8	8	S7 and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2005/10/15 19:11

		(#4E40600# #E4E2000# 1	LIC BODY ID	00	140	2005/10/04 15 01
S9	11	("4548688" "5173393" "5347040" "5487967" "5858621" "5879856" "6045981" "6096484" "6124405" "6127097" "6280908").PN. OR ("6709807").	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/04 15:04
		URPN.				2005/40/45 15 15
S10	485	semiconductor and (lithograph\$2 same (heat with (line or coat\$3 or photoresist)))	US-PGPUB; USPAT	OR	ON	2005/10/15 19:18
S11	398	S10 and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2005/10/15 19:21
S12	42	S11 and smooth\$5 and rough\$4	US-PGPUB; USPAT	OR	ON	2005/10/15 20:21
S13	0	semiconductor and ((thermal adj ablation) same (smooth\$5 and rough\$4))	US-PGPUB; USPAT	OR	ON	2005/10/15 19:20
S14	118	(((thermal or laser) near2 ablat\$3) same (smooth\$5 and rough\$4))	US-PGPUB; USPAT	OR	ON	2005/10/15 19:21
S15	102	S14 and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2005/10/15 20:22
S16	1	("2003/0192167").URPN.	USPAT	OR	ON	2005/10/15 19:27
S17	54	((smooth\$5 with edge\$2) with heat\$3) same rough\$4	US-PGPUB; USPAT	OR	ON	2005/10/15 20:22
S18	45	S17 and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2005/10/15 20:32
S19	1	("6602794").PN. OR ("6905949"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/15 20:27
S20	1	"6905949".pn. and heat\$3	US-PGPUB; USPAT	OR	ON	2005/10/15 20:32
S21	1	("6602794").PN. OR ("6905949"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/15 20:35
S22	112	356/636.ccls. and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2005/10/16 16:21
S23	961	356/630,601,625.ccls. and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2006/02/05 16:24
S24	0	S23 and heat\$3 and (edge adj roughness) and photoresist	US-PGPUB; USPAT	OR	ON	2005/10/16 16:24
S25	0	S23 and heat\$3 and (edge adj roughness)	US-PGPUB; USPAT	OR	ON	2006/02/05 16:32
S26	1	S23 and (edge adj roughness)	US-PGPUB; USPAT	OR	ON	2005/10/16 16:24
S27	264	heat\$3 and (edge adj roughness) and photoresist	US-PGPUB; USPAT	OR	ON	2005/10/16 16:26
S28	118	S27 and (critical or CD)	US-PGPUB; USPAT	OR	ON	2005/10/16 16:25

S29	3	heat\$3 and (edge adj roughness) and photoresist	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/16 16:26
S30	976	356/630,601,625.ccls. and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2006/02/05 19:24
S31	0	S30 and heat\$3 and (edge adj roughness)	US-PGPUB; USPAT	OR	ON	2006/02/05 16:36
S32	3	S30 and heat\$3 and reflow	US-PGPUB; USPAT	OR	ON	2006/02/05 16:33
S33	0	reflow and heat\$3 and (edge adj roughness) and (critical adj dimension\$1)	US-PGPUB; USPAT	OR	ON	2006/02/05 19:27
S34	92	heat\$3 and (edge adj roughness) and (critical adj dimension\$1)	US-PGPUB; USPAT	OR	ON	2006/02/05 19:26
S35	53	S34 and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2006/02/05 16:59
S36	0	S35 and "356"/\$.ccls.	US-PGPUB; USPAT	OR	ON	2006/02/05 16:37
S37	11	("4548688" "5173393" "5347040" "5487967" "5858621" "5879856" "6045981" "6096484" "6124405" "6127097" "6280908").PN. OR ("6709807"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/05 16:58
S38	11	S37 and @ad<="20030822"	US-PGPUB; USPAT	OR	ON	2006/02/05 16:59
S39	1	("6602794").PN. OR ("6905949"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/05 17:00
S40	9	("5173393" "5487967" - "5858621" "5879856" "6045981" "6124405" "6127097").PN. OR ("6582891").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/05 17:00